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Form P FO-1449 (REV. 8-83)	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 107615		APPLICATION NO. 09/688,961
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(REV. 8-83)		PATENT & TRADEMARK OFFICE	107615	•	09/68	8,961			
INFORMATION DISCLOSURE STATEMENT			:			•			
(Use several sheets if necessary)				APPLICANT(S) Alain BETHUNE					
							GROUP 1734		
		U.S. P	ATENT DOC	CUMENTS					
EXAMINER INITIAL	>	DOCUMENT NUMBER	DATE	DATE NAME		CLASS	SUB CLASS 34.4 2003		
	1	5,487,927	1/30/96	KAMEN ET AL.		128 P E	34.4		
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		DOCUMENT NUMBER	DATE	COUNT	RY	CLASS	SUB CLASS		
D	2	JP 1-202492 with Abstract	8/15/89	JAPAN					
Hal	3	JP 1-141086 with Abstract	6/2/89	JAPAN					
	4	JP 8-39997 with Abstract	2/13/96	JAPAN					
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)									
AI	5	Partial English-language translation of JP 1-202492							
1 8	6	Partial English-language translation of JP 1-141086 6/89							
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EXAMINER					DATE CONSIDERED				
	Initial in	f citation considered, whether or not citation ance/and not considered. Include copy of			609; draw line th	rough citat	ion if not in		

Date: March 24, 2003